

Florian F Krause

List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/6898024/publications.pdf>

Version: 2024-02-01

27
papers

787
citations

623734

14
h-index

526287

27
g-index

33
all docs

33
docs citations

33
times ranked

916
citing authors

#	ARTICLE	IF	CITATIONS
1	Atomic electric fields revealed by a quantum mechanical approach to electron picodiffraction. Nature Communications, 2014, 5, 5653.	12.8	232
2	Measurement of atomic electric fields and charge densities from average momentum transfers using scanning transmission electron microscopy. Ultramicroscopy, 2017, 178, 62-80.	1.9	106
3	Effects of instrument imperfections on quantitative scanning transmission electron microscopy. Ultramicroscopy, 2016, 161, 146-160.	1.9	55
4	Theoretical study of precision and accuracy of strain analysis by nano-beam electron diffraction. Ultramicroscopy, 2015, 158, 38-48.	1.9	43
5	Nanosopic Insights into InGaN/GaN Core-Shell Nanorods: Structure, Composition, and Luminescence. Nano Letters, 2016, 16, 5340-5346.	9.1	43
6	Materials characterisation by angle-resolved scanning transmission electron microscopy. Scientific Reports, 2016, 6, 37146.	3.3	33
7	Comparison of first moment STEM with conventional differential phase contrast and the dependence on electron dose. Ultramicroscopy, 2019, 203, 95-104.	1.9	29
8	Comparison of intensity and absolute contrast of simulated and experimental high-resolution transmission electron microscopy images for different multislice simulation methods. Ultramicroscopy, 2013, 134, 94-101.	1.9	25
9	Conventional Transmission Electron Microscopy Imaging beyond the Diffraction and Information Limits. Physical Review Letters, 2014, 113, 096101.	7.8	21
10	Influence of plasmon excitations on atomic-resolution quantitative 4D scanning transmission electron microscopy. Scientific Reports, 2020, 10, 17890.	3.3	21
11	Quantitative HAADF STEM of SiGe in presence of amorphous surface layers from FIB preparation. Ultramicroscopy, 2018, 184, 29-36.	1.9	17
12	Strain analysis from nano-beam electron diffraction: Influence of specimen tilt and beam convergence. Ultramicroscopy, 2018, 190, 45-57.	1.9	17
13	Using molecular dynamics for multislice TEM simulation of thermal diffuse scattering in AlGaN. Ultramicroscopy, 2018, 189, 124-135.	1.9	16
14	Influence of distortions of recorded diffraction patterns on strain analysis by nano-beam electron diffraction. Ultramicroscopy, 2019, 196, 74-82.	1.9	15
15	Homogeneity and composition of AlInGaN: A multiprobe nanostructure study. Ultramicroscopy, 2015, 156, 29-36.	1.9	14
16	Optimization of NBED simulations for disc-detection measurements. Ultramicroscopy, 2017, 181, 50-60.	1.9	13
17	Influence of Static Atomic Displacements on Composition Quantification of AlGaN/GaN Heterostructures from HAADF-STEM Images. Microscopy and Microanalysis, 2014, 20, 1463-1470.	0.4	11
18	Measurement of local crystal lattice strain variations in dealloyed nanoporous gold. Materials Research Letters, 2018, 6, 84-92.	8.7	10

#	ARTICLE	IF	CITATIONS
19	Accurate measurement of strain at interfaces in 4D-STEM: A comparison of various methods. Ultramicroscopy, 2021, 221, 113196.	1.9	10
20	4D-STEM at interfaces to GaN: Centre-of-mass approach & NBED-disc detection. Ultramicroscopy, 2021, 228, 113321.	1.9	9
21	Angle-resolved STEM using an iris aperture: Scattering contributions and sources of error for the quantitative analysis in Si. Ultramicroscopy, 2021, 221, 113175.	1.9	8
22	Precise measurement of the electron beam current in a TEM. Ultramicroscopy, 2021, 223, 113221.	1.9	8
23	Reciprocity relations in transmission electron microscopy: A rigorous derivation. Micron, 2017, 92, 1-5.	2.2	6
24	Towards the interpretation of a shift of the central beam in nano-beam electron diffraction as a change in mean inner potential. Ultramicroscopy, 2022, 236, 113503.	1.9	6
25	Imaging theory for the ISTEM imaging mode. Ultramicroscopy, 2017, 181, 107-116.	1.9	5
26	Angle-dependence of ADF-STEM intensities for chemical analysis of InGaN/GaN. Ultramicroscopy, 2022, 238, 113535.	1.9	4
27	Accuracy and precision of position determination in ISTEM imaging of BaTiO ₃ . Ultramicroscopy, 2021, 227, 113325.	1.9	2